

A new procedure has been developed that determines the complex refractive index of a material in the soft X-ray regime by consistently considering simultaneous measurements of electron yield and reflectance. Note that each synchrotron has a preferred method of handling the

arriving Dewars, and busy synchrotrons often have tens of Dewars a day passing through the Goods Handling Office, so correct labeling of the Dewar is critical.

Related Books

- [Antilliaanse jeugdliteratuur](#)
- [Men of letters and the English public in the eighteenth century, 1660-1744.](#)
- [Microsoft Word 5.5 made easy](#)
- [Proceso de ocupación espacial y poblamiento al sur del Río Miriñay, 1769-1869](#)
- [Process and quality control and calibration programs of the National Bureau of Standards](#)